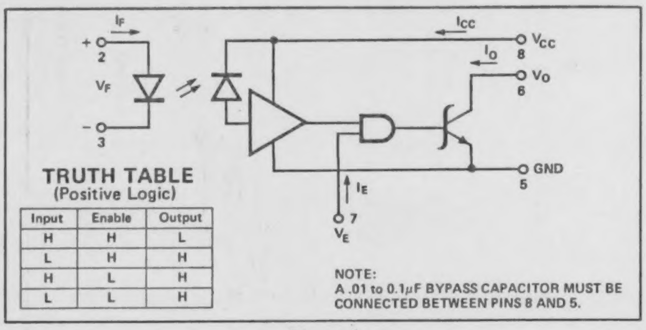
HEWLETT PACKARD

COMPONENTS

LSTTL/TTL COMPATIBLE OPTOCOUPLER

6N137

TECHNICAL DATA APRIL 1979



TRUTH TABLE
(Positive Logic)

Input	Enable	Output
H	H	L
L	H	H
H	L	H
L	L	H

Figure 1.

Features

- LSTTL/TTL COMPATIBLE: 5V SUPPLY
- ULTRA HIGH SPEED
- LOW INPUT CURRENT REQUIRED
- HIGH COMMON MODE REJECTION
- GUARANTEED PERFORMANCE OVER TEMPERATURE
- RECOGNIZED UNDER THE COMPONENT PROGRAM OF UNDERWRITERS LABORATORIES, INC. (FILE NO. E55361)
- 3000V dc INSULATION VOLTAGE

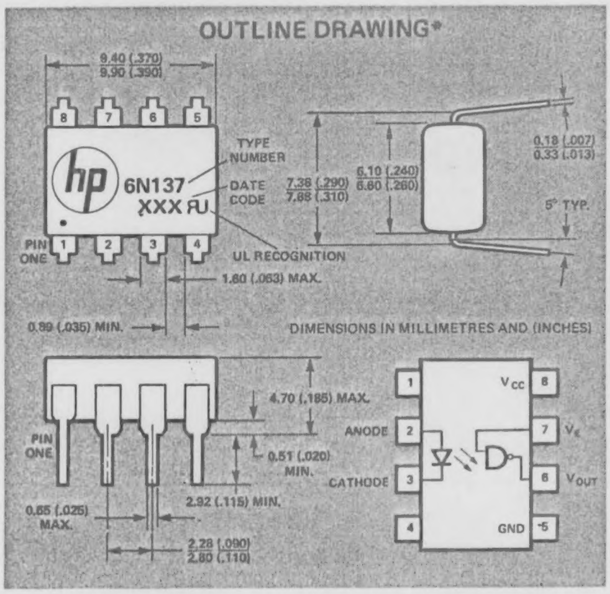
Description Applications

The 6N137 consists of a GaAsP photon emitting diode and a unique integrated detector. The photons are collected in the detector by a photodiode and then amplified by a high gain linear amplifier that drives a Schottky clamped open collector output transistor. The circuit is temperature, current and voltage compensated.

This unique isolator design provides maximum DC and AC circuit isolation between input and output while achieving LSTTL/TTL circuit compatibility. The isolator operational parameters are guaranteed from 0°C to 70°C, such that a minimum input current of 5mA will sink an eight gate fan-out (13mA) at the output with 5 volt V_{CC} applied to the detector. This isolation and coupling is achieved with a typical propagation delay of 45ns. The enable input provides gating of the detector with input sinking and sourcing requirements compatible with LSTTL/TTL interfacing and a propagation delay of 25ns typical.

The 6N137 can be used in high speed digital interfacing applications where common mode signals must be rejected, such as for a line receiver and digital programming of floating power supplies, motors, and other machine control systems. The elimination of ground loops can be accomplished in system interfaces such as between a computer and a peripheral memory, printer, controller, etc.

The open collector output provides capability for bussing, OR'ing and strobing.



Recommended Operating Conditions

	Sym.	Min.	Max.	Units
Input Current, Low Level Each Channel	I_{FL}	0	250	μA
Input Current, High Level Each Channel	I_{FH}	6.3**	15	mA
High Level Enable Voltage	V_{EH}	2.0	Vcc	V
Low Level Enable Voltage (Output High)	V_{EL}	0	0.8	V
Supply Voltage, Output	V_{CC}	4.5	5.5	V
Fan Out (TTL Load)	N		8	
Operating Temperature	T_A	0	70	°C

Absolute Maximum Ratings*

(No derating required up to 70°C)

Storage Temperature .... –55°C to +125°C
Operating Temperature .... 0°C to +70°C
Lead Solder Temperature .... 260°C for 10s
(1.6mm below seating plane)
Peak Forward Input
Current .... 40mA (1≤ 1msec Duration)
Average Forward Input Current 20mA
Reverse Input Voltage 5V
Enable Input Voltage 5.5V
(Not to exceed V_{CC} by more than 500mV)
Supply Voltage - V_{CC} .... 7V (1 Minute Maximum)
Output Current - I_O 50mA
Output Collector Power Dissipation 85mW
Output Voltage - V_O 7V

**6.3mA condition permits at least 20% CTR degradation guardband. Initial switching threshold is 5mA or less.

*JEDEC Registered Data.

Electrical Characteristics

OVER RECOMMENDED TEMPERATURE (T_A = 0°C TO 70°C) UNLESS OTHERWISE NOTED

Parameter	Symbol	Min.	Typ.**	Max.	Units	Test Conditions	Figure	Note
High Level Output Current	I_{OH}*		50	250	μA	V_{CC}=5.5V, V_O=5.5V, I_F=250μA, V_E=2.0V	6	
Low Level Output Voltage	V_{OL}*		0.5	0.6	V	V_{CC}=5.5V, I_F=5mA, V_{EH}=2.0V I_{OL} (Sinking) =13mA	3,5	
High Level Enable Current	I_{EH}		-1.0		mA	V_{CC}=5.5V, V_E=2.0V		
Low Level Enable Current	I_{EL}*		-1.6	-2.0	mA	V_{CC}=5.5V, V_E=0.5V		
High Level Supply Current	I_{CCH}*		7	15	mA	V_{CC}=5.5V, I_F=0 V_E=0.5V		
Low Level Supply	I_{CCL}*		13	18	mA	V_{CC}=5.5V, I_F=10mA V_E=0.5V		
Input-Output Insulation Leakage Current	I_{I-O}*			1.0	μA	Relative Humidity=45% T_A=25°C, t=5s V_{I-O}=3000Vdc		5
Resistance (Input-Output)	R_{I-O}		10^{12}		Ω	V_{I-O}=500V, T_A=25°C		5
Capacitance (Input-Output)	C_{I-O}		0.6		pF	f=1MHz, T_A=25°C		5
Input Forward Voltage	V_F*		1.5	1.75	V	I_F=10mA, T_A=25°C	4	8
Input Reverse Breakdown Voltage	BV_R*	5			V	I_R=10μA, T_A=25°C		
Input Capacitance	C_{IN}		60		pF	V_F=0, f=1MHz		
Current Transfer Ratio	CTR		700		%	I_F=5.0mA, R_L=100Ω	2	7

**All typical values are at V_{CC} = 5V, T_A = 25°C

OPTO-COUPLERS

Switching Characteristics at T_A=25°C, V_{CC}=5V

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions	Figure	Note
Propagation Delay Time to High Output Level	t_{PLH}*		45	75	ns	R_L=350Ω, C_L=15pF, I_F=7.5mA	7,9	1
Propagation Delay Time to Low Output Level	t_{PHL}*		45	75	ns	R_L=350Ω, C_L=15pF, I_F=7.5mA	7,9	2
Output Rise-Fall Time (10-90%)	t_r, t_f		25		ns	R_L=350Ω, C_L=15pF, I_F=7.5mA		
Propagation Delay Time of Enable from V_{EH} to V_{EL}	t_{ELH}		25		ns	R_L=350Ω, C_L=15pF, I_F=7.5mA, V_{EH}=3.0V, V_{EL}=0.5V	8	3
Propagation Delay Time of Enable from V_{EL} to V_{EH}	t_{EHL}		15		ns	R_L=350Ω, C_L=15pF, I_F=7.5mA V_{EH}=3.0V, V_{EL}=0.5V	8	4
Common Mode Transient Immunity at Logic High Output Level	CM_H		50		v/μs	V_{CM}=10V R_L=350Ω, V_O(min.)=2V, I_F=0mA	11	6
Common Mode Transient Immunity at Logic Low Output Level	CM_L		-150		v/μs	V_{CM}=10V R_L=350Ω, V_O(max.)=0.8V, I_F=5mA	11	6

*JEDEC Registered Data.

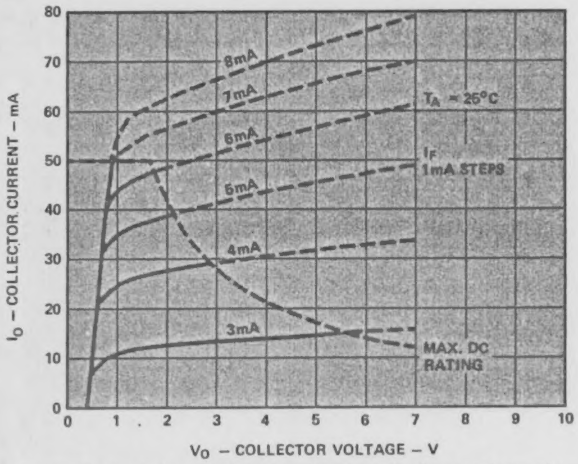
Operating Procedures and Definitions

Logic Convention. The 6N137 is defined in terms of positive logic.

Bypassing. A ceramic capacitor (.01 to 0.1μF) should be connected from pin 8 to pin 5 (Figure 12). Its purpose is to stabilize the operation of the high gain linear amplifier. Failure to provide the bypassing may impair the switching properties. The total lead length between capacitor and coupler should not exceed 20mm.

Polarities. All voltages are referenced to network ground (pin 5). Current flowing toward a terminal is considered positive.

Enable Input. No external pull-up required for a logic (1), i.e., can be open circuit.



Note: Dashed characteristics — denote pulsed operation only.

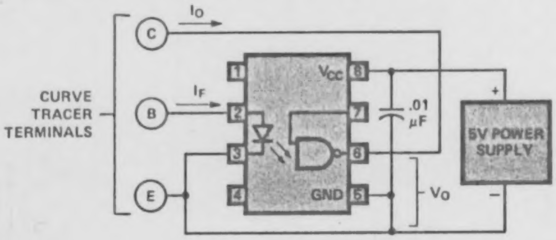
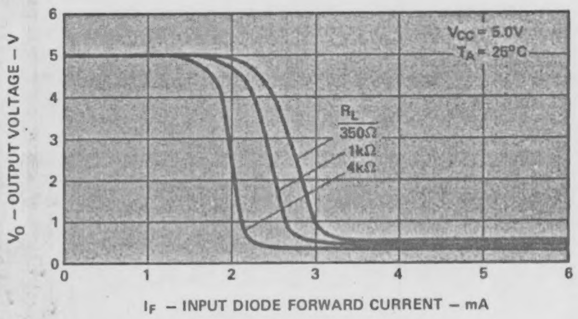


Figure 2. Optocoupler Collector Characteristics.



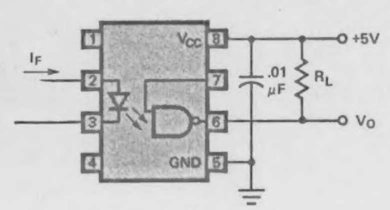


Figure 3. Input-Output Characteristics.

NOTES:

1. The t_{PLH} propagation delay is measured from the 3.75mA point on the trailing edge of the input pulse to the 1.5V point on the trailing edge of the output pulse.
2. The t_{PHL} propagation delay is measured from the 3.75mA point on the leading edge of the input pulse to 1.5V point on the leading edge of the output pulse.
3. The t_{ELH} enable propagation delay is measured from the 1.5V point of the trailing edge of the input pulse to the 1.5V point on the trailing edge of the output pulse.
4. The t_{EHL} enable propagation delay is measured from the 1.5V point on the leading edge of the input pulse to the 1.5V point on the leading edge of the output pulse.
5. Device considered a two terminal device: pins 2 and 3 shorted together, and pins 5, 6, 7, and 8 shorted together.
6. Common mode transient immunity in Logic High level is the maximum tolerable (positive) dV_{CM}/dt on the leading edge of the common mode pulse, V_{CM}, to assure that the output will remain in a Logic High state (i.e., $V_O > 2.0V$). Common mode transient immunity in Logic Low level is the maximum tolerable (negative) dV_{CM}/dt on the trailing edge of the common mode pulse signal, V_{CM}, to assure that the output will remain in a Logic Low state (i.e., $V_O < 0.8V$).
7. DC Current Transfer Ratio is defined as the ratio of the output collector current to the forward bias input current times 100%.
8. At 10mA V_F decreases with increasing temperature at the rate of 1.6mV/°C.

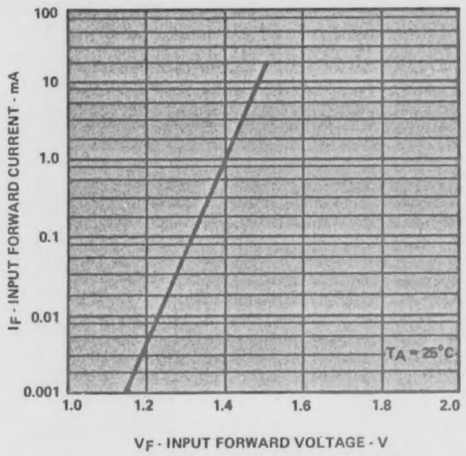


Figure 4. Input Diode Forward Characteristic.

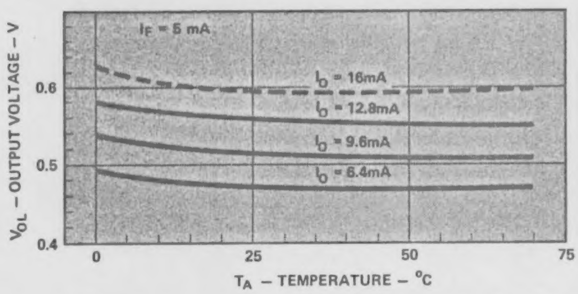


Figure 5. Output Voltage, V_{OL} vs. Temperature and Fan-Out.

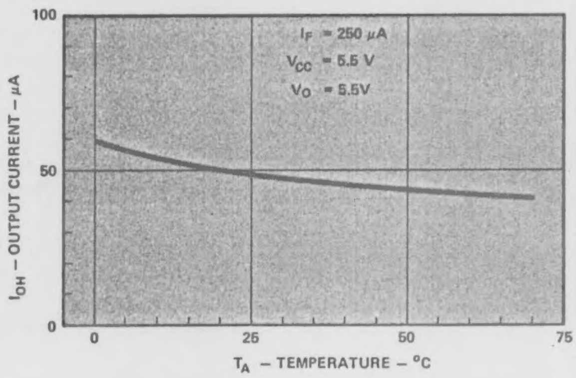


Figure 6. Output Current, I_{OH} vs. Temperature (I_F=250μA).

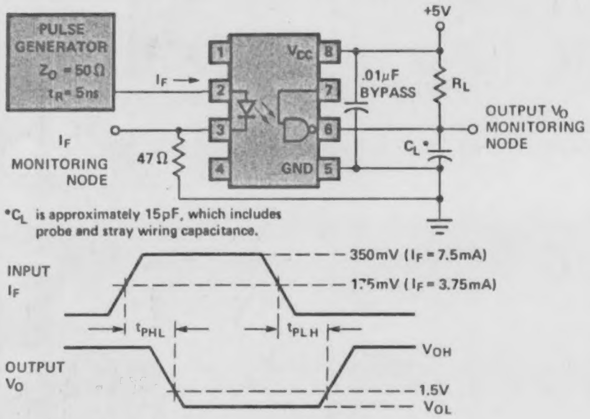


Figure 7. Test Circuit for t_{PHL} and t_{PLH}.**

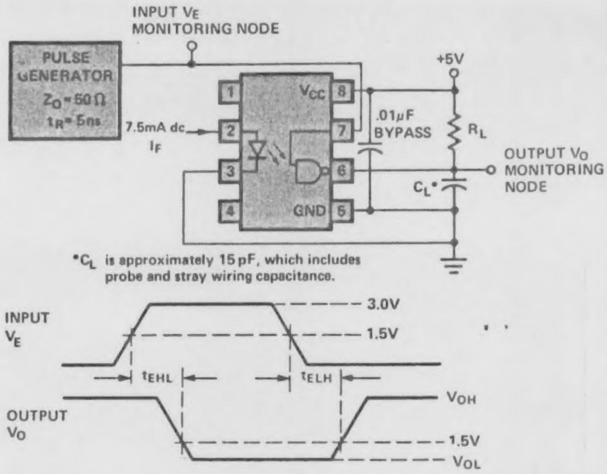


Figure 8. Test Circuit for t_{ELH} and t_{EHL}.

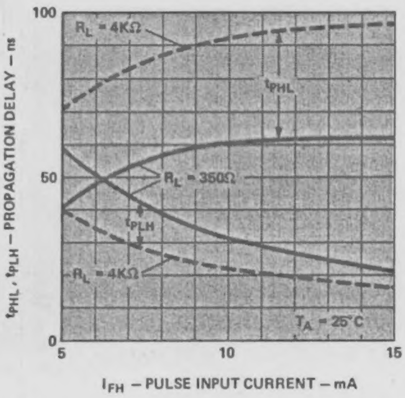


Figure 9. Propagation Delay, t_{PHL} and t_{PLH} vs. Pulse Input Current, I_{FH}.

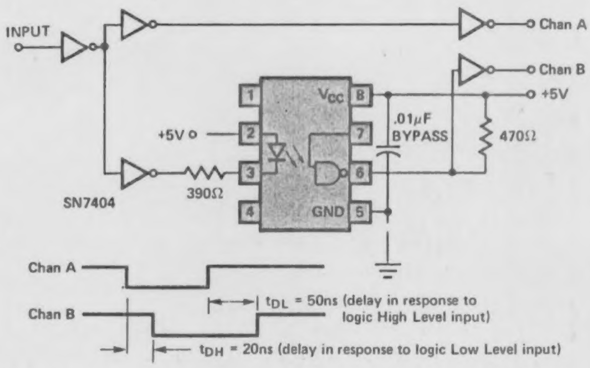


Figure 10. Response Delay Between TTL Gates.

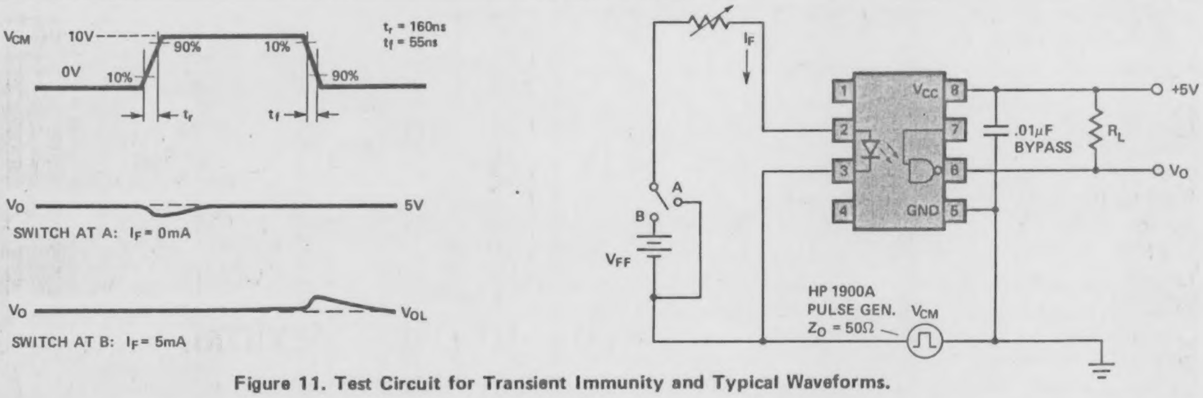


Figure 11. Test Circuit for Transient Immunity and Typical Waveforms.

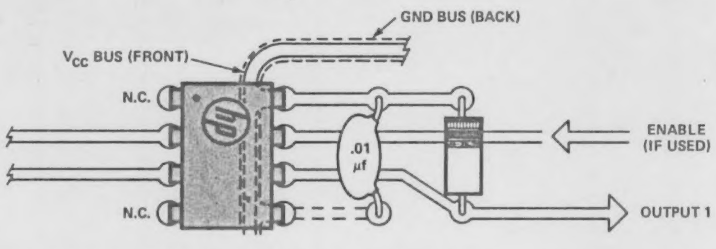


Figure 12. Recommended Printed Circuit Board Layout.

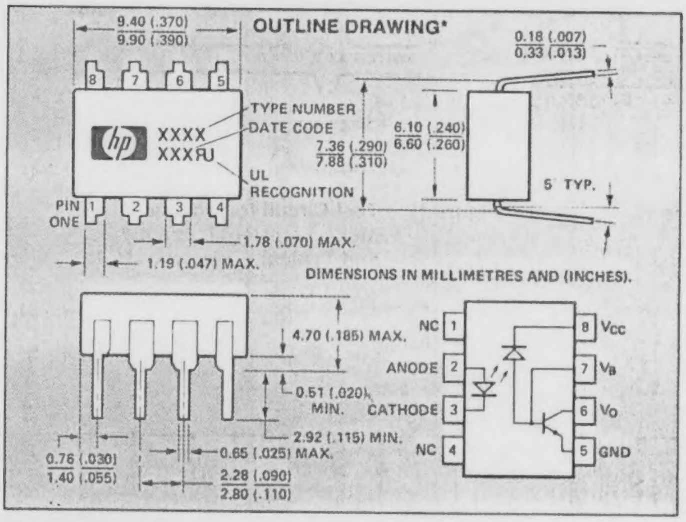
** JEDEC Registered Data.

LOW INPUT CURRENT, HIGH GAIN OPTOCOUPLERS

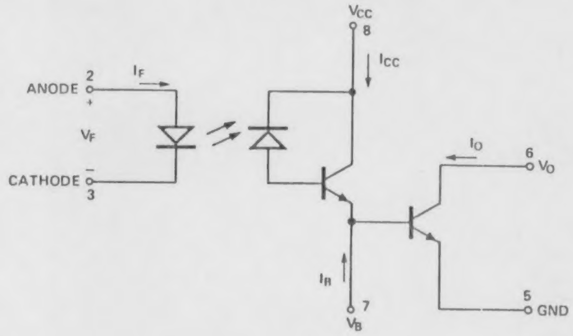
HEWLETT PACKARD

6N138
6N139

TECHNICAL DATA JANUARY 1984



SCHEMATIC



Features

- HIGH CURRENT TRANSFER RATIO — 800% TYPICAL
- LOW INPUT CURRENT REQUIREMENT — 0.5 mA
- TTL COMPATIBLE OUTPUT — 0.1 V V_{OL} TYPICAL
- HIGH COMMON MODE REJECTION — 500 V/μs
- PERFORMANCE GUARANTEED OVER TEMPERATURE 0°C to 70°C
- BASE ACCESS ALLOWS GAIN BANDWIDTH ADJUSTMENT
- HIGH OUTPUT CURRENT — 60 mA
- 100K BITS/SEC TYPICAL SPEED AT I_F = 0.5 mA
- DIELECTRIC WITHSTAND TESTED AT 3000 Vdc FOR A WORKING VOLTAGE OF 220 Vac
- RECOGNIZED UNDER THE COMPONENT PROGRAM OF UNDERWRITERS LABORATORIES, INC. (FILE NO. E55361)

Description

These high gain series couplers use a Light Emitting Diode and an integrated high gain photon detector to provide extremely high current transfer ratio between input and output. Separate pins for the photodiode and output stage result in TTL compatible saturation voltages and high speed operation. Where desired the V_{CC} and V_O terminals may be tied together to achieve conventional photodarlington operation. A base access terminal allows a gain bandwidth adjustment to be made.

The 6N139 is suitable for use in CMOS, LSTTL or other low power applications. A 400% minimum current transfer ratio is guaranteed over a 0-70°C operating range for only 0.5 mA of LED current.

The 6N138 is suitable for use mainly in TTL applications. Current Transfer Ratio is 300% minimum over 0-70°C for an LED current of 1.6 mA [1 TTL unit load (U.L.)]. A 300% minimum CTR enables operation with 1 U.L. in, 1 U.L. out with a 2.2 kΩ pull-up resistor.

Applications

- Ground Isolate Most Logic Families – TTL/TTL, CMOS/TTL, CMOS/CMOS, LSTTL/TTL, CMOS/LSTTL
- Low Input Current Line Receiver – Long Line or Party line
- EIA RS-232C Line Receiver
- Telephone Ring Detector
- 117 V ac Line Voltage Status Indicator – Low Input Power Dissipation
- Low Power Systems – Ground Isolation

Absolute Maximum Ratings*

Storage Temperature	−55°C to +125°C
Operating Temperature	0°C to +70°C
Lead Solder Temperature	260°C for 10s (1.6mm below seating plane)
Average Input Current – I_F	20mA [1]
Peak Input Current – I_F	40mA (50% duty cycle, 1 ms pulse width)
Peak Transient Input Current – I_F	1.0A (≤ 1μs pulse width, 300 pps)
Reverse Input Voltage – V_R	5V
Input Power Dissipation	35mW [2]
Output Current – I_O (Pin 6)	60mA [3]
Emitter-Base Reverse Voltage (Pin 5-7)	0.5V
Supply and Output Voltage – V_{CC} (Pin 8-5), V_O (Pin 6-5)	
6N138	−0.5 to 7V
6N139	−0.5 to 18V
Output Power Dissipation	100mW [4]

See notes, following page.

CAUTION: The small junction sizes inherent to the design of this bipolar component increases the component's susceptibility to damage from electrostatic discharge (ESD). It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation which may be induced by ESD.

*JEDEC Registered Data.

Electrical Specifications

OVER RECOMMENDED TEMPERATURE (T_A = 0°C to 70°C), UNLESS OTHERWISE SPECIFIED

Parameter	Sym.	Device	Min.	Typ.**	Max.	Units	Test Conditions	Fig.	Note
Current Transfer Ratio	CTR*	6N139	400 500	800 900		%	I_F = 0.5mA, V_O = 0.4V, V_{CC} = 4.5V I_F = 1.6mA, V_O = 0.4V, V_{CC} = 4.5V	3	5,6
		6N138	300	600		%	I_F = 1.6mA, V_O = 0.4V, V_{CC} = 4.5V		
Logic Low Output Voltage	V_{OL}	6N139		0.1 0.1 0.2	0.4 0.4 0.4	V	I_F = 1.6mA, I_O = 6.4mA, V_{CC} = 4.5V I_F = 5mA, I_O = 15mA, V_{CC} = 4.5V I_F = 12mA, I_O = 24mA, V_{CC} = 4.5V	1,2	6
		6N138		0.1	0.4	V	I_F = 1.6mA, I_O = 4.8mA, V_{CC} = 4.5V		
Logic High Output Current	I_{OH}*	6N139		0.05	100	µA	I_F = 0mA, V_O = V_{CC} = 18V		6
		6N138		0.1	250	µA	I_F = 0mA, V_O = V_{CC} = 7V		
Logic Low Supply Current	I_{CCL}			0.2		mA	I_F = 1.6mA, V_O = Open, V_{CC} = 5V		6
Logic High Supply Current	I_{CCH}			10		nA	I_F = 0mA, V_O = Open, V_{CC} = 5V		6
Input Forward Voltage	V_F*			1.4	1.7	V	I_F = 1.6mA, T_A = 25°C	4	
Input Reverse Breakdown Voltage	BV_R*		5		V		I_R = 10µA, T_A=25°C		
Temperature Coefficient of Forward Voltage	$\frac{\Delta V_F}{\Delta T_A}$			−1.8		mV/°C	I_F = 1.6mA		
Input Capacitance	C_{IN}			60		pF	f=1MHz, V_F = 0		
Input - Output Insulation Leakage Current	$I_{I\text{-}O}$*				1.0	µA	45% Relative Humidity, T_A = 25°C t = 5 s, $V_{I\text{-}O}$ = 3000Vdc		7,11
Resistance (Input-Output)	$R_{I\text{-}O}$			10^{12}		Ω	$V_{I\text{-}O}$ = 500Vdc		7
Capacitance (Input-Output)	$C_{I\text{-}O}$			0.6		pF	f = 1MHz		7

**All typicals at T_A = 25°C and V_{CC} = 5V, unless otherwise noted.

Switching Specifications

AT T_A = 25°C

Parameter	Sym.	Device	Min.	Typ.	Max.	Units	Test Conditions	Fig.	Note
Propagation Delay Time To Logic Low at Output	t_{PHL}*	6N139		5 0.2	25 1	µs	I_F = 0.5mA, R_L = 4.7kΩ I_F = 12mA, R_L = 270Ω	9	6,8
		6N138		1	10	µs	I_F = 1.6mA, R_L = 2.2kΩ		
Propagation Delay Time To Logic High at Output	t_{PLH}*	6N139		5 1	60 7	µs	I_F = 0.5mA, R_L = 4.7kΩ I_F = 12mA, R_L = 270Ω	9	6,8
		6N138		4	35	µs	I_F = 1.6mA, R_L = 2.2kΩ		
Common Mode Transient Immunity at Logic High Level Output	CM_H			500		V/µs	I_F = 0mA, R_L = 2.2kΩ, R_{CC} = 0 $\|V_{cm}\|$ = 10$V_{p\text{-}p}$	10	9,10
Common Mode Transient Immunity at Logic Low Level Output	CM_L			−500		V/µs	I_F = 1.6mA, R_L = 2.2kΩ, R_{CC} = 0 $\|V_{cm}\|$ = 10$V_{p\text{-}p}$	10	9,10

NOTES:

1. Derate linearly above 50°C free-air temperature at a rate of 0.4mA/°C.
2. Derate linearly above 50°C free-air temperature at a rate of 0.7mW/°C.
3. Derate linearly above 25°C free-air temperature at a rate of 0.7mA/°C.
4. Derate linearly above 25°C free-air temperature at a rate of 2.0mW/°C.
5. DC CURRENT TRANSFER RATIO is defined as the ratio of output collector current, I_O, to the forward LED input current, I_F, times 100%.
6. Pin 7 Open.
7. Device considered a two-terminal device: Pins 1, 2, 3, and 4 shorted together and Pins 5, 6, 7, and 8 shorted together.
8. Use of a resistor between pin 5 and 7 will decrease gain and delay time. See Application Note 951-1 for more details.
9. Common mode transient immunity in Logic High level is the maximum tolerable (positive) dV_{cm}/dt on the leading edge of the common mode pulse, V_{cm}, to assure that the output will remain in a Logic High state (i.e., $V_O > 2.0V$). Common mode transient immunity in Logic Low level is the maximum tolerable (negative) dV_{cm}/dt on the trailing edge of the common mode pulse signal, V_{cm}, to assure that the output will remain in a Logic Low state (i.e., $V_O < 0.8V$).
10. In applications where dV/dt may exceed 50,000V/µs (such as static discharge) a series resistor, R_{CC}, should be included to protect the detector IC from destructively high surge currents. The recommended value is $R_{CC} \approx \frac{1V}{0.15\ I_F\ (mA)}$ kΩ.
11. This is a proof test to validate the UL 220 Vac rating.

*JEDEC Registered Data.

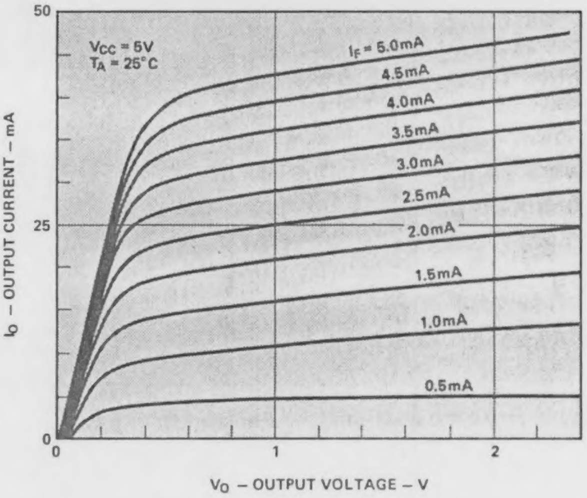


Figure 1. 6N139 DC Transfer Characteristics.

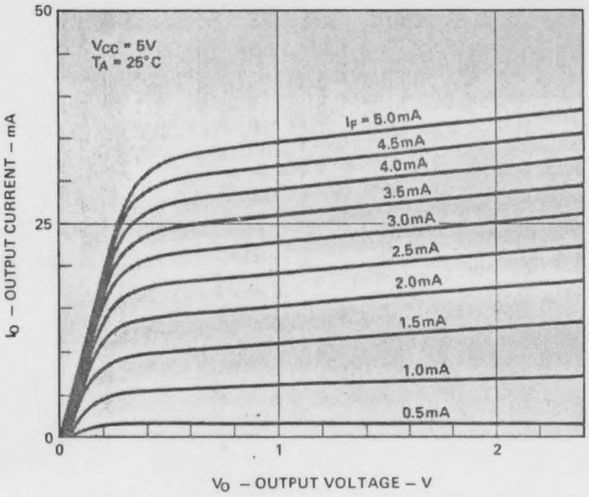


Figure 2. 6N138 DC Transfer Characteristics.

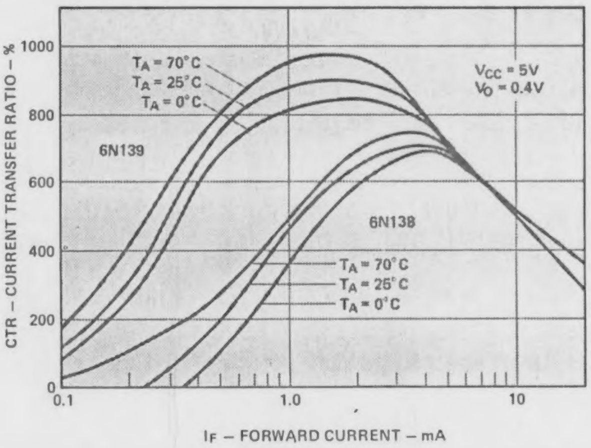


Figure 3. Current Transfer Ratio vs. Forward Current.

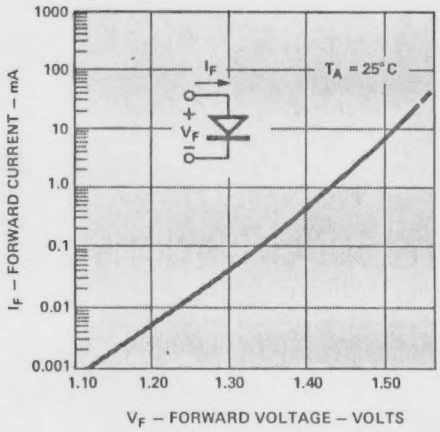


Figure 4. Input Diode Forward Current vs. Forward Voltage.

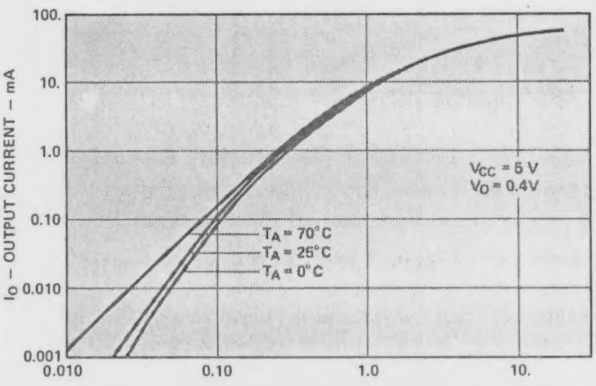


Figure 5. 6N139 Output Current vs. Input Diode Forward Current.

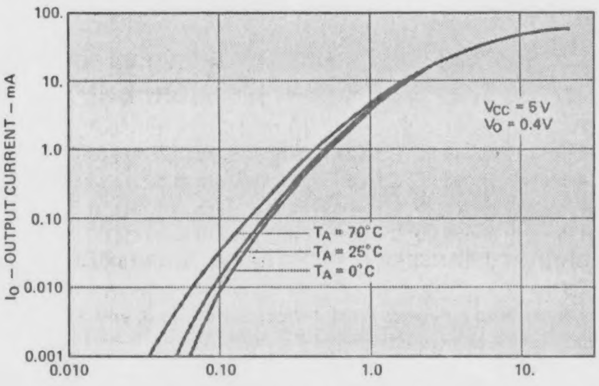


Figure 6. 6N138 Output Current vs. Input Diode Forward Current.

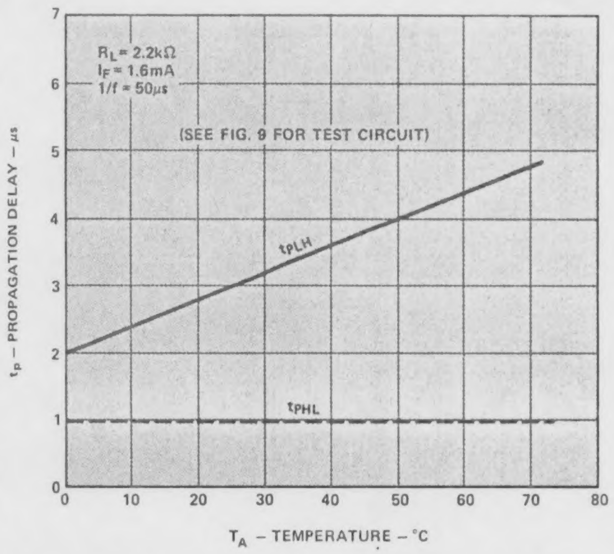


Figure 7. Propagation Delay vs. Temperature.

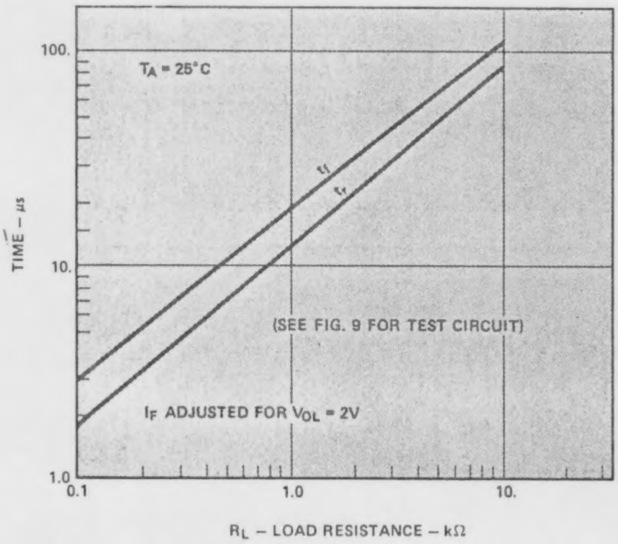


Figure 8. Non Saturated Rise and Fall Times vs. Load Resistance.

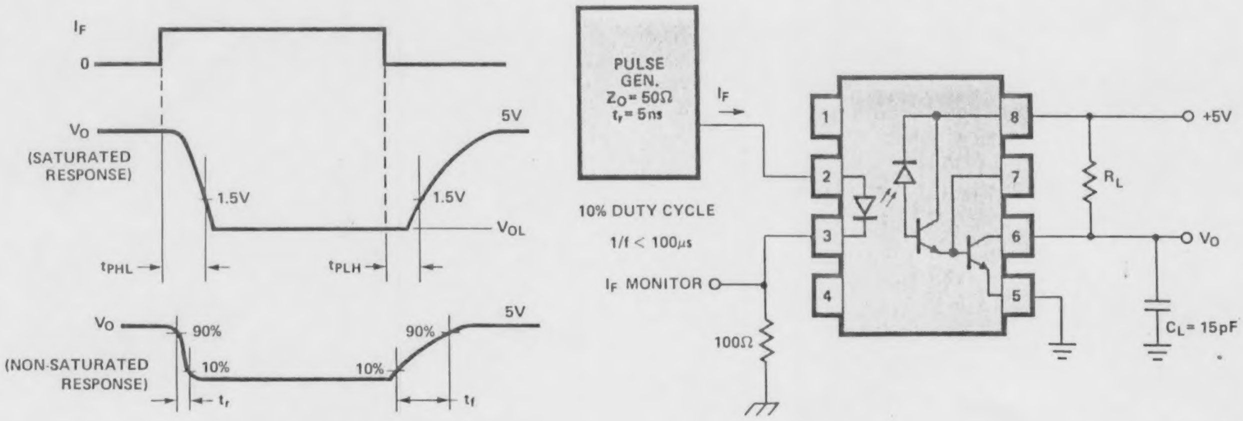


Figure 9. Switching Test Circuit.*

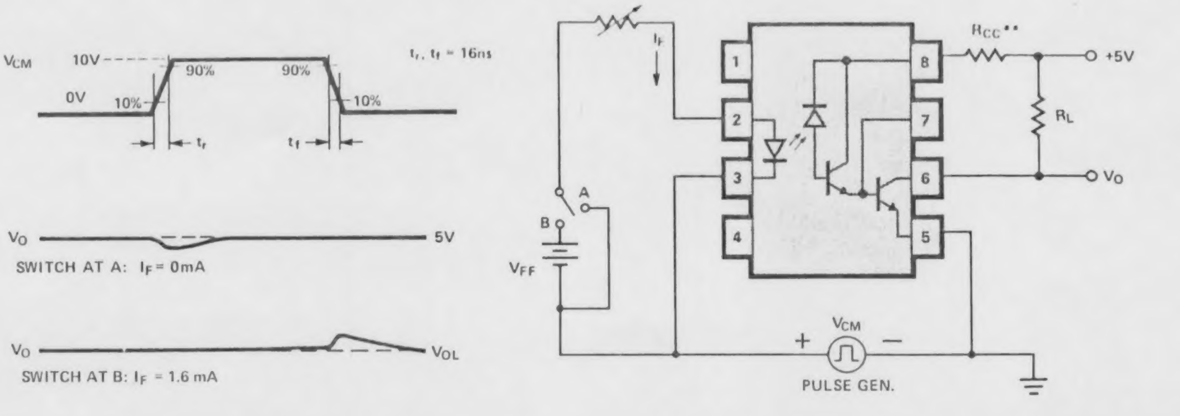


Figure 10. Test Circuit for Transient Immunity and Typical Waveforms.

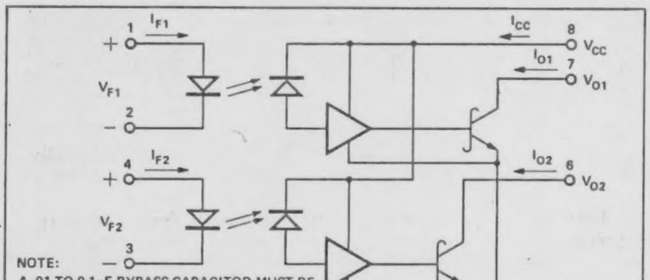
*JEDEC Registered Data.

**See Note 10

DUAL TTL COMPATIBLE OPTOCOUPLER

HCPL-2630

TECHNICAL DATA APRIL 1979



NOTE:
A .01 TO 0.1µF BYPASS CAPACITOR MUST BE CONNECTED BETWEEN PINS 8 AND 5.

Figure 1.

Features

- HIGH DENSITY PACKAGING
- DTL/TTL COMPATIBLE: 5V SUPPLY
- ULTRA HIGH SPEED
- LOW INPUT CURRENT REQUIRED
- HIGH COMMON MODE REJECTION
- GUARANTEED PERFORMANCE OVER TEMPERATURE
- RECOGNIZED UNDER THE COMPONENT PROGRAM OF UNDERWRITERS LABORATORIES, INC. (FILE NO. E55361)
- 3000Vdc INSULATION VOLTAGE

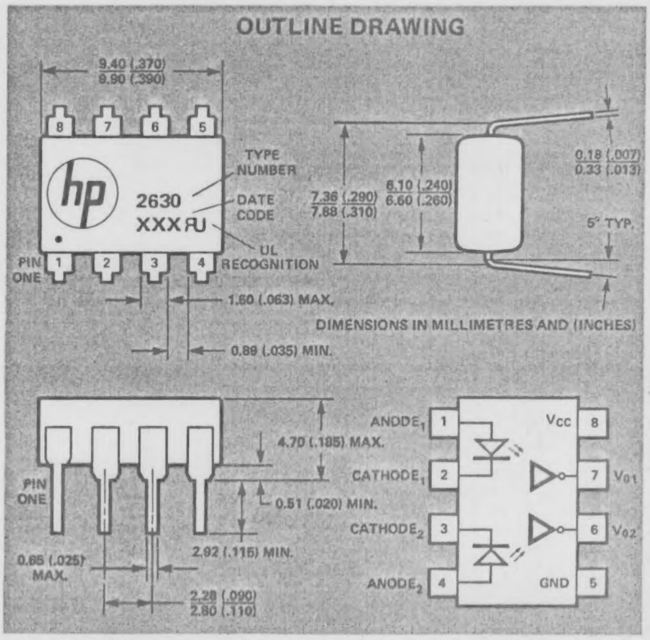
Description/Applications

The HCPL-2630 consists of a pair of inverting optically coupled gates each with a GaAsP photon emitting diode and a unique integrated detector. The photons are collected in the detector by a photodiode and then amplified by a high gain linear amplifier that drives a Schottky clamped open collector output transistor. Each circuit is temperature, current and voltage compensated.

This unique dual coupler design provides maximum DC and AC circuit isolation between each input and output while achieving DTL/TTL circuit compatibility. The coupler operational parameters are guaranteed from 0°C to 70°C, such that a minimum input current of 5 mA in each channel will sink an eight gate fan-out (13 mA) at the output with 5 volt V_{CC} applied to the detector. This isolation and coupling is achieved with a typical propagation delay of 50 nsec.

The HCPL-2630 can be used in high speed digital interface applications where common mode signals must be rejected such as for a line receiver and digital programming of floating power supplies, motors, and other machine control systems. The elimination of ground loops can be accomplished between system interfaces such as between a computer and a peripheral memory, printer, controller, etc.

The open collector output provides capability for bussing, strobing and "WIRED-OR" connection. In all applications, the dual channel configuration allows for high density packaging, increased convenience and more usable board space.



Recommended Operating Conditions

	Sym.	Min.	Max.	Units
Input Current, Low Level Each Channel	I_{FL}	0	250	µA
Input Current, High Level Each Channel	I_{FH}	6.3*	15	mA
Supply Voltage, Output	V_{CC}	4.5	5.5	V
Fan Out (TTL Load) Each Channel	N		8	
Operating Temperature	T_A	0	70	°C

Absolute Maximum Ratings

(No derating required up to 70°C)

Storage Temperature .... -55°C to +125°C
Operating Temperature .... 0°C to +70°C
Lead Solder Temperature .... 260°C for 10s
(1.6mm below seating plane)
Peak Forward Input
Current (each channel) ..... 30 mA (≤ 1 msec Duration)
Average Forward Input Current (each channel) ..... 15 mA
Reverse Input Voltage (each channel) 5V
Supply Voltage – V_{CC} .... 7V (1 Minute Maximum)
Output Current – I_O (each channel) .... 16 mA
Output Voltage – V_O (each channel) 7V
Output Collector Power Dissipation .... 60 mW

*6.3mA condition permits at least 20% CTR degradation guardband. Initial switching threshold is 5mA or less.

Electrical Characteristics

OVER RECOMMENDED TEMPERATURE (T_A = 0°C TO 70°C) UNLESS OTHERWISE NOTED

Parameter	Symbol	Min.	Typ.*	Max.	Units	Test Conditions	Figure	Note
High Level Output Current	I_{OH}		50	250	μA	V_{CC} = 5.5V, V_O = 5.5V, I_F = 250μA		3
Low Level Output Voltage	V_{OL}		0.5	0.6	V	V_{CC} = 5.5V, I_F = 5mA I_{OL} (Sinking) = 13mA	3	3
High Level Supply Current	I_{CCH}		14	30	mA	V_{CC} = 5.5V, I_F = 0 (Both Channels)		
Low Level Supply	I_{CCL}		26	36	mA	V_{CC} = 5.5V, I_F = 10mA (Both Channels)		
Input - Output Insulation Leakage Current	I_{I-O}			1.0	μA	Relative Humidity = 45% T_A = 25°C, t = 5s, V_{I-O} = 3000Vdc		4
Resistance (Input-Output)	R_{I-O}		10^{12}		Ω	V_{I-O} = 500V, T_A = 25°C		4
Capacitance (Input-Output)	C_{I-O}		0.6		pF	f = 1MHz, T_A = 25°C		4
Input Forward Voltage	V_F		1.5	1.75	V	I_F = 10mA, T_A = 25°C	4	7,3
Input Reverse Breakdown Voltage	BV_R	5			V	I_R = 10μA, T_A = 25°C		
Input Capacitance	C_{IN}		60		pF	V_F = 0, f = 1MHz		3
Input-Input Insulation Leakage Current	I_{I-I}		0.005		μA	Relative Humidity = 45%, t=5s, V_{I-I}=500V		8
Resistance (Input-Input)	R_{I-I}		10^{11}		Ω	V_{I-I} = 500V		8
Capacitance (Input-Input)	C_{I-I}		0.25		pF	f = 1MHz		8
Current Transfer Ratio	CTR		700		%	I_F = 5.0mA, R_L = 100Ω	2	6

*All typical values are at V_{CC} = 5V, T_A = 25°C

Switching Characteristics at T_A=25°C, V_{CC}=5V

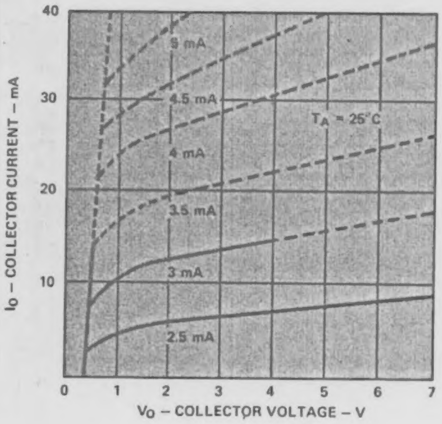
EACH CHANNEL

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions	Figure	Note
Propagation Delay Time to High Output Level	t_{PLH}		55	75	ns	R_L = 350 Ω, C_L = 15pF, I_F = 7.5mA	6,7	1
Propagation Delay Time to Low Output Level	t_{PHL}		40	75	ns	R_L = 350 Ω, C_L = 15pF, I_F = 7.5mA	6,7	2
Output Rise-Fall Time (10-90%)	t_r, t_f		25		ns	R_L = 350 Ω, C_L = 15pF, I_F = 7.5mA		
Common Mode Transient Immunity at High Output Level	CM_H		50		V/μs	V_{CM} = $10V_{p-p}$, R_L = 350 Ω, V_O (min.) = 2V, I_F = 0mA	9	5
Common Mode Transient Immunity at Low Output Level	CM_L		-150		V/μs	V_{CM} = $10V_{p-p}$, R_L = 350 Ω, V_O (max.) = 0.8V I_F = 7.5mA	9	5

NOTE: It is essential that a bypass capacitor (.01μF to 0.1μF, ceramic) be connected from pin 8 to pin 5. Total lead length between both ends of the capacitor and the isolator pins should not exceed 20mm. Failure to provide the bypass may impair the switching properties (Figure 5).

NOTES:

1. The t_{PLH} propagation delay is measured from the 3.75 mA point on the trailing edge of the input pulse to the 1.5V point on the trailing edge of the output pulse.
2. The t_{PHL} propagation delay is measured from the 3.75 mA point on the leading edge of the input pulse to the 1.5V point on the leading edge of the output pulse.
3. Each channel.
4. Measured between pins 1, 2, 3, and 4 shorted together, and pins 5, 6, 7, and 8 shorted together.
5. Common mode transient immunity in Logic High level is the maximum tolerable (positive) dV_{CM}/dt on the leading edge of the common mode pulse, V_{CM}, to assure that the output will remain in a Logic High state (i.e., $V_O>2.0V$). Common mode transient immunity in Logic Low level is the maximum tolerable (negative) dV_{CM}/dt on the trailing edge of the common mode pulse signal, V_{CM}, to assure that the output will remain in a Logic Low state (i.e., $V_O<0.8V$).
6. DC Current Transfer Ratio is defined as the ratio of the output collector current to the forward bias input current times 100%.
7. At 10mA VF decreases with increasing temperature at the rate of 1.9mV/°C.
8. Measured between pins 1 and 2 shorted together, and pins 3 and 4 shorted together.



NOTE: Dashed characteristics indicate pulsed operation.

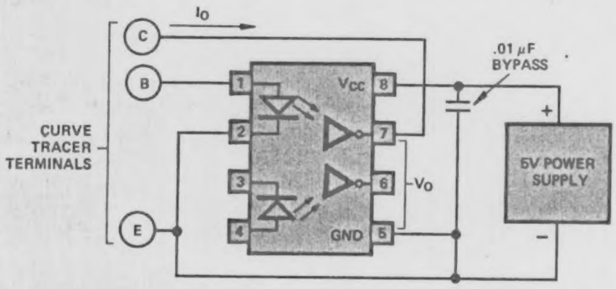


Figure 2. Optocoupler Transfer Characteristics.

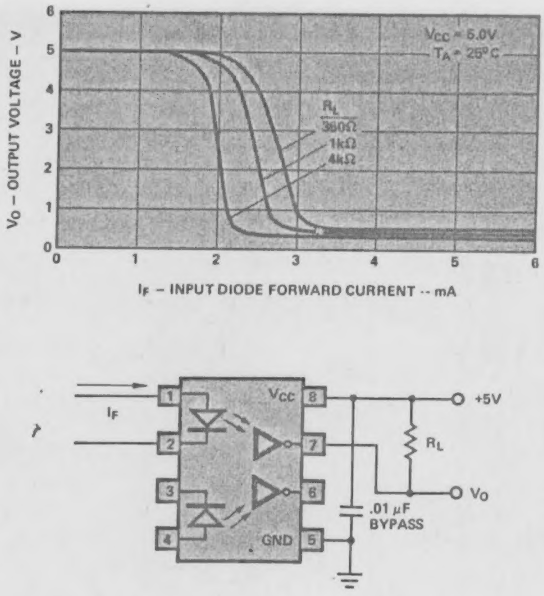


Figure 3. Input-Output Characteristics.

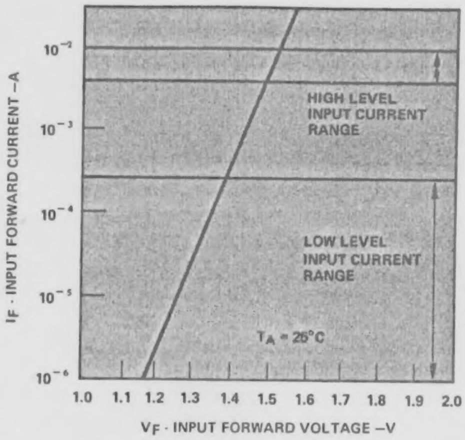


Figure 4. Input Diode Forward Characteristic

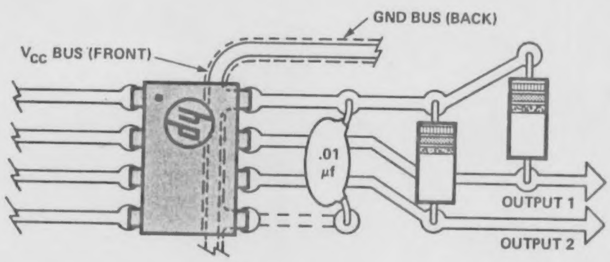


Figure 5. Recommended Printed Circuit Board Layout.

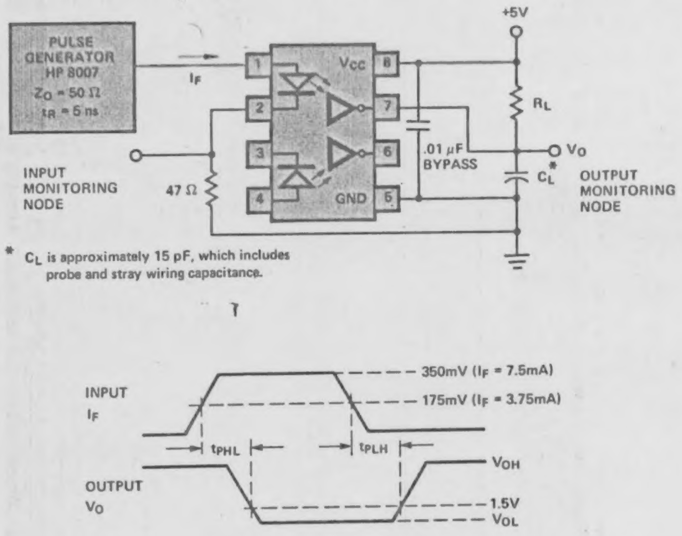


Figure 6. Test Circuit for t_{PHL} and t_{PLH}.

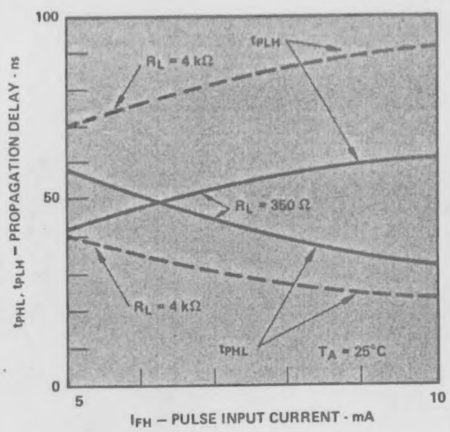


Figure 7. Propagation Delay, t_{PHL} and t_{PLH} vs. Pulse Input Current, I_{FH}.

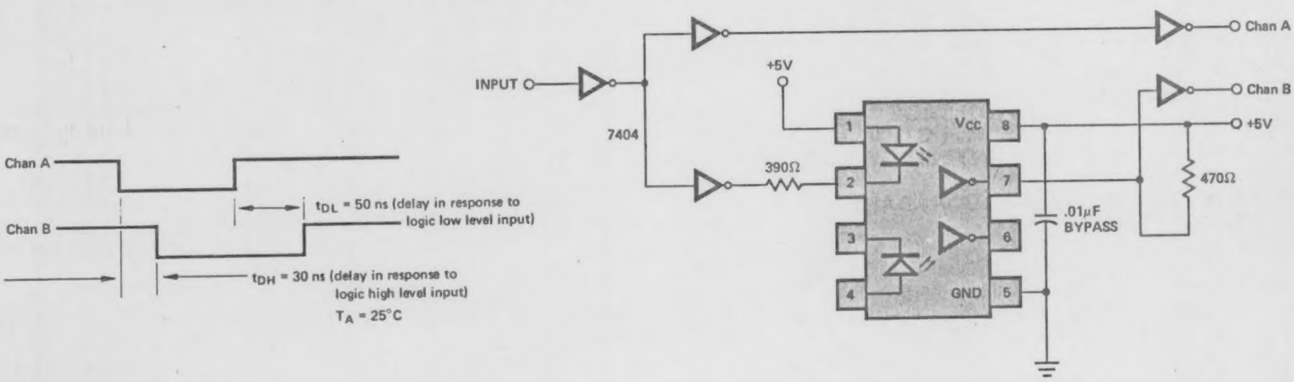


Figure 8. Response Delay Between TTL Gates.

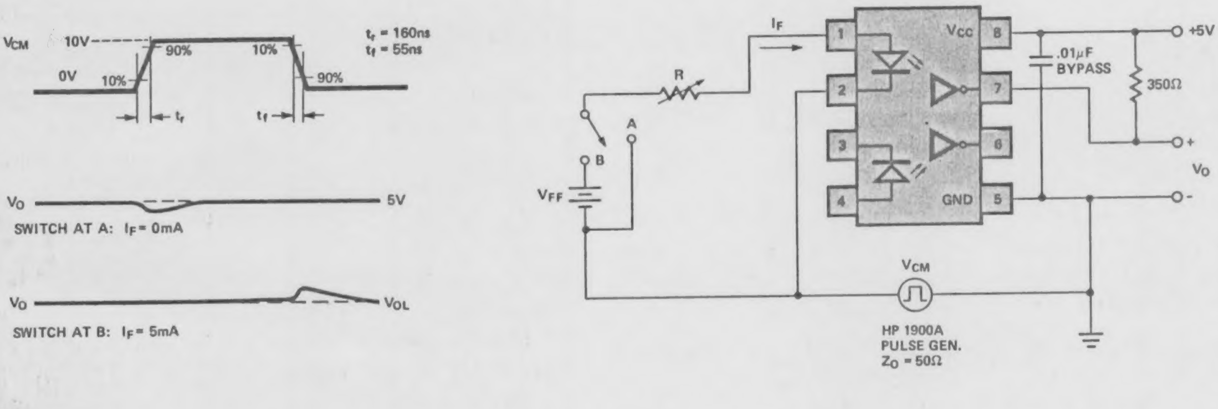


Figure 9. Test Circuit for Transient Immunity and Typical Waveforms.